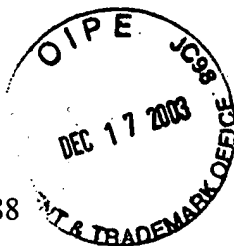


Docket No.: 50090-288



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PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

|  |   |                           |
|--|---|---------------------------|
| In re Application of   | : | Customer Number: 20277    |
| Toshiaki OHMORI  | : | Confirmation Number: 3783 |
| Serial No.: 09/826,038   | : | Group Art Unit: 1765      |
| Filed: April 05, 2001  | : | Examiner: K.C. Chen       |
| For: METHOD FOR MANUFACTURING SEMICONDUCTOR DEVICE USING<br>PREDETERMINED MEASUREMENT VALUE (As amended) | : |                           |

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop Information Disclosure  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection or Notice of Allowance, but before payment of the Issue Fee.

**REQUEST TO CONSIDER REFERENCES AFTER CLOSE OF PROSECUTION AND**

**BEFORE PAYMENT OF ISSUE FEE**

The undersigned hereby requests consideration and entry of this Information Disclosure Statement and accompanying references under 37 CFR 1.97(d).

Please charge the processing fee under 1.17(p) of \$180.00 to Deposit Account 500417.

12/18/2003 JBALINAN 00000136 500417 09826038

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CERTIFICATION PARAGRAPH

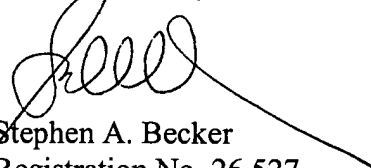
The undersigned certifies that, to the best of his knowledge, each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement as described in 37 CFR 1.97(e)(1).

Each non-English language reference was cited in a corresponding foreign application search report or office action and its relevance discussed therein. A copy of the foreign search report or office action, together with an English language version thereof, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

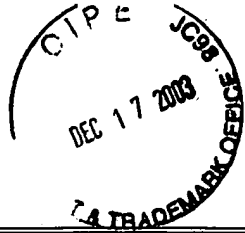
Respectfully submitted,

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**Date: December 17, 2003**



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
**50090-288**SERIAL NO.  
**09/826,038**APPLICANT  
**Toshiaki OHMORI**FILING DATE  
**April 05, 2001**GROUP  
**1765**

## U.S. PATENT DOCUMENTS

| EXAMINER'S INITIALS | CITE NO. | Document Number<br>Number-Kind Code <sup>2</sup> (if known) | Publication Date<br>MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear |
|---------------------|----------|---|--------------------------------|---|---|
|                     |          | US  |                                |   |   |
|                     |          | US  |                                |   |   |
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## FOREIGN PATENT DOCUMENTS

| EXAMINER'S INITIALS | CITE NO. | Foreign Patent Document<br>Country Codes - Number - Kind<br>Codes (if known) | Publication Date<br>MM-DD-YYYY | Name of Patentee or<br>Applicant of Cited Document | Pages, Columns, Lines<br>Where Relevant<br>Figures Appear | Translation |    |
|---------------------|----------|--|--------------------------------|--|---|-------------|----|
|                     |          |  |                                |  |   | Yes         | No |
|                     |          | KR 1999-0054210 (corres. to JP 11-354453)                                    | 07/15/1999                     |  |   |             |    |
|                     |          | JP 11-354453 (w/ English Abstract)   | 12/24/1999                     | SAMSUNG ELECTRONICS CO., LTD.                      |   |             |    |
|                     |          | JP 10-163286 (w/ English Abstract)   | 06/19/1998                     | NEC CORP.  |   |             |    |
|                     |          |  |                                |  |   |             |    |
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